

METHOD AND APPARATUS FOR ORIENTING A CRYSTALLINE BODY
DURING RADIATION DIFFRACTOMETRY

ABSTRACT OF THE DISCLOSURE

The method and apparatus of the present invention permit indirect identification of a target plane, such as the plane identified by an alignment feature, 5 based upon the identification of a reference plane which is offset by a predetermined angle from the target plane. In addition, in order to permit alignment features to be defined at non-standard angles with respect to the axial orientation of an ingot, an apparatus is provided that includes a frame having at least two members. The first member abuts a bar extending outwardly from the stage of an x-ray diffractometer, 10 while the second member carries an engagement member for engaging a non-standard alignment feature. The second member may be movable relative to the first member to permit the frame to be mounted upon ingots having different non-standard alignment features.

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